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INFORMATION DISCLOSURE CITATION <small>(Use several sheets if necessary)</small>				Docket Number (Optional) Y0R920010368US2		Application Number 10/059,422	
				Applicant(s) Bojarczuk, Jr., et al.			
				Filing Date January 31, 2002	Group Art Unit 2814		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TD		3,986,197	10/12/76	Ablasmeier	{	{	{
TD		6,376,337 B1	04/23/02	Wang et al	{	{	{
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (including Author, Title, Date, Pertinent Page, Etc.)							
EXAMINER	2 Drawn	DATE CONSIDERED					
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. YOR92001-3US2	SERIAL NO. Not Yet Assigned		
				APPLICANT(S) Bojarczuk, Jr. et al.	FILING DATE Concurrently Herewith	GROUP 2814 Not Yet Assigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
11017 U.S. PTO 10/05/22 01/31/02							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
11017 U.S. PTO 10/05/22 01/31/02							
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
TD		"Crystalline Oxides on Silicon: The First Five Monolayers", Rodney A. McKee et al., Physical Review Letters, Volume 81, Number 14, October 5, 1998, pp. 3014-3017.					
TD		"Epitaxial Ceo2 on Silicon Substrates and the Potential of Si/ceo2/si for SOI Structures", A.H. Morshed et al., Mat. Res. Soc. Symp. V474, 339(1997).					
EXAMINER <i>2/10/03</i>			DATE CONSIDERED <i>03/11/03</i>				

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